

FORM HDP-149 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE  
INFORMATION DISCLOSURE CITATION**

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Sheet 1 of 2

ATTORNEY DOCKET NO.

4858-000123

SERIAL NO.

09/484,799

APPLICANT

Jeremy Barker

FILING DATE

January 18, 2000

GROUP

1745

**U.S. PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	CL	5,871,866	2/16/99	Barker et al.		
2.	CL	5,567,548	10/22/96	Walk et al.		
3.	CL	5,496,663	3/5/96	Walk et al.		
4.	CL	5,219,677	6/15/93	Labat et al.		

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	CL	PCT/US00/35302	5/29/01	Search Report - PCT			
2.	CL	EP 1 049 182 A2	11/2/00	Europe			X
3.	CL	JP11025983	1999-01/1999	Japan		X	
4.	CL	DE 40 24 409 A1	8/1/90	Germany			X
5.	CL	JP5299101	1994-11/1993	Japan		X	
6.	CL	JP11111295	11/1999	Japan		X	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

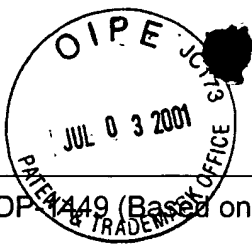
Ref. Desig.	Examiner's Initials	
1.	CL	Boutinaud et al., "The Solid Solution BaLi <sub>1-x</sub> Cu <sub>x</sub> PO <sub>4</sub> ( $x \leq 0.5$ ): An Example of Cu+ Single-Ion Luminescence in Oxide Insulators"; J. Mater. Chem 1996, 6(3), pp 381-384.
2.	CL	Patent Abstracts of Japan, 11025983, 1/29/99, Japan Storage Battery Col., Ltd.
3.	CL	Patent Abstracts of Japan, 05299101, 11/12/93, Sanyo Electric Co., Ltd.

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Date Considered:

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**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.	<i>a</i>	Patent Abstracts of Japan, 1111295, 4/23/99, Japan Storage Battery Co., Ltd.
2.	<i>a</i>	Goni et al., "7Li and 31P Nuclear Magnetic Resonance Studies of Li <sub>1-3x</sub> Mg <sub>x</sub> Fe <sub>x</sub> PO <sub>4</sub> "; Journal of Applied Physics, Volume 84, Number 1, July 1, 1998, pp 416-421.
3.	<i>a</i>	Nanjundaswamy et al., "Synthesis, Redox Potential Evaluation and Electrochemical Characteristics of NASICON-Related-3D Framework Compounds"; Solid State Ionics 92 (1996) pp 1-10.
4.	<i>a</i>	Gopalakrishnan et al., "V <sub>2</sub> (PO <sub>4</sub> ) <sub>3</sub> : A Novel NASICON-Type Vanadium Phosphate Synthesized by Oxidative Deintercalation of Sodium from Na <sub>3</sub> V <sub>2</sub> (PO <sub>4</sub> ) <sub>3</sub> "; Chemistry of Materials, Volume 4, Number 4, July/August 1992.
5.	<i>a</i>	Martinez-Juarez et al., "Relationship Between Activation Energy and Bottleneck Size for Li <sup>+</sup> Ion Conduction in NASICON Materials of Composition LiMM'(PO <sub>4</sub> ) <sub>3</sub> ; M, M' = Ge, Ti, Sn, Hf"; J. Phys. Chem, 1998, pp 372-375.
6.	<i>a</i>	Cocciantelli et al., "On the $\delta \rightarrow \gamma$ Irreversible Transformation in Li//V <sub>2</sub> O <sub>5</sub> Secondary Batteries," Solid State Ionics 78 (1995) pp 143-150.
7.	<i>a</i>	Delmas et al., "The Li <sub>x</sub> V <sub>2</sub> O <sub>5</sub> System: An Overview of the Structure Modifications Induced by the Lithium Intercalation"; Solid State Ionics, 69 (1994) pp 257-264.

Examiner:

*Chen*

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11-19-01

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